Serial No.: 10/749,704

Filed: December 31, 2003

Page : 2 of 15

AMENDMENTS TO THE CLAIMS:

This listing of claims replaces all prior versions and listings of claims in the application:

LISTING OF CLAIMS:

1. (Currently Amended) A testing architecture for automatic test equipment, comprising:

a signal source; and

a plurality of source/capture channels comprising one source/capture channel and remaining source/capture channels, said signal source coupled to at least the one source/capture channel of said channels being coupled to the signal source, the signal source being configured to provide for providing a signal cancellation signal to reduce for reducing an amplitude of a signal received by said the one source/capture channel, the one source/capture channel comprising:

a first combiner configured to receive a signal under test and a baseline signal and configured to provide a first combiner output signal; and

a second combiner configured to receive the first combiner output signal and configured to provide a second combiner output signal.

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 3 of 15

2. (Currently Amended) The architecture of claim 1 wherein said signal source the one source/capture channel further comprises a Digital-to-Analog Converter (DAC) configured to provide the baseline signal to the first combiner.

- 3. (Currently Amended) The architecture of claim 1, wherein said system further comprising comprises an external adjustment device coupled between said the source and said the plurality of source/capture channels.
- 4. (Currently Amended) The architecture of claim 1 wherein at least one of said at least the one source/capture channel further channels comprises a capture an Analog-to-Digital Converter (ADC) configured to receive the second combiner output signal capable of receiving a signal from a device under test.
- 5. (Currently Amended) The architecture of claim 4 wherein at least one of said at least one source/capture channels further comprises a the second combiner is configured to receive receiving a cancellation signal from said the signal source, receiving a signal under test, and providing a residual signal from said cancellation signal and said signal under test to said ADC.
- 6. (Currently Amended) The architecture of claim 4 wherein the at least one of said at least one source/capture channels channel further comprises:

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 4 of 15

test; and

a combiner receiving a cancellation signal from said signal source, receiving a signal under test, and providing an output signal from said cancellation signal and said signal under

an amplifier <u>configured to receive receiving said</u> the second <u>combiner</u> output signal from said <u>combiner</u> and <u>configured to provide providing</u> an output <u>signal</u> to <u>said</u> the ADC.

7. (Cancelled)

8. (Currently Amended) The architecture of claim 1 wherein at least one of said at least the one source/capture channels channel comprises:

a first combiner receiving a signal under test and a baseline signal, and providing a first combiner output signal;

a second combiner receiving a cancellation signal from said signal source, receiving said first combiner output signal and providing a second combiner output signal; and

an amplifier <u>configured to receive the receiving said</u> second combiner output signal and <u>configured to provide providing</u> a residual signal to <u>said an Analog-to-Digital Converter (ADC)</u>

ADC.

9. (Currently Amended) The architecture of claim 4 wherein at least one of said at least the one source/capture channel channels further comprises an amplifier configured to receive

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 5 of 15

receiving a signal from said the signal source and configured to provide providing an output to a the device under test.

10. (Currently Amended) The architecture of claim 4 wherein at least one of said at least the one source/capture channel channels further comprises a Digital-to-Analog (DAC) configured to provide providing an output to a the device under test.

11. (Currently Amended) The architecture of claim 1 wherein said the architecture is operable in a first mode wherein each channel of the plurality of source/capture channels is configured to perform a multiple capture, each channel configured substantially the same as the one source/capture channel comprising:

a first combiner receiving a signal under test and a baseline signal, and providing a first combiner output signal;

a second combiner receiving said first combiner output signal and providing a second combiner output signal; and

an amplifier receiving said second combiner output signal and providing a residual signal to said ADC.

Serial No. : 10/749,704

Filed: December 31, 2003

Page : 6 of 15

12. (Currently Amended) The architecture of claim 1 wherein said-device the architecture is operable in a second mode wherein the one source/capture channel of said

plurality of channels is configured to perform a capture with signal cancellation,

wherein said channel comprising:

a first combiner receiving a signal under test and a baseline signal, and providing a first

combiner output signal;

a the second combiner is configured to receive receiving a cancellation signal from said

the signal source, receiving said first combiner output signal and providing a second combiner

output signal; and

an amplifier receiving said second combiner output signal and providing a residual signal

to said ADC.

13. (Currently Amended) The architecture of claim 1 wherein said the architecture is

operable in a third mode wherein each channel of said the plurality of source/capture channels is

configured to perform a capture with signal cancellation, each channel configured substantially

the same as the one source/capture channel eomprising:

wherein a first combiner receiving a signal under test and a baseline signal, and

providing a first combiner output signal;

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 7 of 15

a the second combiner is configured to receive receiving a cancellation signal from said

the signal source, receiving said first combiner output signal and providing a second combiner

output signal; and

an amplifier receiving said second-combiner output signal and providing a residual signal

to said ADC.

14. (Currently Amended) The architecture of claim 12 wherein said in the second mode

further comprises the remaining channels of said the plurality of channels are configured to

perform a multiple capture, each of said the remaining channels comprising:

a first combiner configured to receive receiving a signal under test and a baseline signal,

and configured to provide providing a first combiner output signal;

a second combiner configured to receive the receiving said first combiner output signal

and configured to provide providing a second combiner output signal; and

an amplifier configured to receive the receiving said second combiner output signal and

configured to provide providing a residual signal to said an ADC.

15. (Currently Amended) A reconfigurable testing architecture for automatic test

equipment, comprising:

a signal source; and

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 8 of 15

a plurality of channels <u>comprising one channel and remaining channels</u>, wherein said <u>the</u> channels are <u>being</u> each configurable into a plurality of modes, each of <u>said</u> <u>the</u> modes providing a different level of precision from another of <u>said</u> <u>the</u> modes.

wherein the one channel comprises:

a first combiner configured to receive a signal under test and a baseline signal, and configured to provide a first combiner output signal; and

a second combiner configured to receive the first combiner output signal and configured to provide a second combiner output signal.

16. (Currently Amended) The architecture of claim 15 wherein said the plurality of modes includes a first mode wherein each channel is configured to perform a multiple capture, each channel being configured substantially the same as the one channel, the one channel further comprising:

a first combiner receiving a signal under test and a baseline signal, and providing a first combiner output signal;

a second combiner receiving said first combiner output signal and providing a second combiner output signal; and

an amplifier receiving said second combiner output signal and providing a residual signal to an <u>Analog-to-Digital Converter (ADC)</u> ADC.

Serial No.: 10/749,704

Filed : 1

: December 31, 2003

Page

: 9 of 15

17. (Currently Amended) The architecture of claim 15 wherein said the plurality of modes includes a second mode wherein the one channel one channel of said plurality of channels is configured to perform a capture with signal cancellation, said the one channel further comprising:

a first combiner receiving a signal under test and a baseline signal, and providing a first combiner output signal;

a second combiner receiving a cancellation signal from said signal source, receiving said first combiner output signal and providing a second combiner output signal; and

an amplifier <u>configured to receive the receiving said</u> second combiner output signal and <u>configured to provide</u> providing a residual signal to an <u>Analog-to-Digital Converter (ADC)</u>

ADC.

18. (Currently Amended) The architecture of claim 15 wherein said the plurality of modes includes a third mode wherein each channel of said the plurality of channels is configured to perform a capture with signal cancellation, each the one channel further comprising:

a first combiner receiving a signal under test and a baseline signal, and providing a first combiner output signal;

a second combiner receiving a cancellation signal from said signal source, receiving said

first combiner output signal and providing a second combiner output signal; and

Serial No.: 10/749,704

Filed : December 31, 2003

Page : 10 of 15

an amplifier configured to receive the receiving said second combiner output signal and configured to provide providing a residual signal to an Analog-to-Digital Converter (ADC) ADC.

19. (Currently Amended) The architecture of claim 17 wherein said in the second mode further comprises the remaining channels of said the plurality of channels are configured to perform a multiple capture, each of said the remaining channels comprising:

a first combiner configured to receive receiving a signal under test and a baseline signal, and configured to provide providing a first combiner output signal;

a second combiner configured to receive the receiving said first combiner output signal and configured to provide providing a second combiner output signal; and

an amplifier configured to receive the receiving said second combiner output signal and configured to provide providing a residual signal to an Analog-to-Digital Converter (ADC) ADC.

20. (New) A testing architecture for automatic test equipment, comprising:

a signal source; and

source/capture channels comprising one source/capture channel and remaining source/capture channels, the one source/capture channel being coupled to the signal source, the

Serial No.: 10/749,704

Filed: December 31, 2003

Page : 11 of 15

signal source being configured to provide a cancellation signal to reduce an amplitude of a signal received by the one source/capture channel, the one source/capture channel comprising:

a first combiner configured to receive a signal under test and a baseline signal and configured to provide a first combiner output signal;

a second combiner configured to receive the first combiner output signal and configured to provide a second combiner output signal;

an Analog-to-Digital Converter (ADC) configured to receive the second combiner output signal; and

a Digital-to-Analog Converter (DAC) configured to provide the baseline signal to the first combiner.

21. (New) The architecture of claim 20, further comprising:

a first amplifier configured to receive the second combiner output signal and configured to provide an output signal to the ADC; and

a second amplifier configured to receive a signal from the signal source and configured to provide an output to the device under test.